

## HEXFET® Power MOSFET

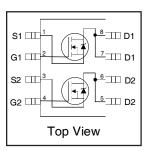
- Advanced Process Technology
- Dual N-Channel MOSFET
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free
- Halogen-Free

V <sub>DSS</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
55V	$0.050 @V_{GS} = 10V$	5.1A
	$0.065@V_{GS} = 4.5V$	4.42A

## **Description**

These HEXFET® Power MOSFET's in a Dual SO-8 package utilize the lastest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of these HEXFET Power MOSFET's are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These benefits combine to make this design an extremely efficient and reliable device for use in a wide variety of other applications.

The 175°C rating for the SO-8 package provides improved thermal performance with increased safe operating area and dual MOSFET die capability make it ideal in a variety of power applications. This dual, surface mount SO-8 can dramatically reduce board space and is also available in Tape & Reel.





Bass Bart Number	Dookogo Typo	Standard Pac	Orderable Part Number	
Base Part Number	Package Type	Form Qua		
IRF7341GPbF	SO-8	Tube/Bulk	95	IRF7341GPbF
INI 754 IGFDF	30-6	Tape and Reel	4000	IRF7341GTRPbF

### **Absolute Maximum Ratings**

	Parameter	Max.	Units	
V <sub>DS</sub>	Drain-Source Voltage	55	V	
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	5.1		
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	4.2	Α	
I <sub>DM</sub>	Pulsed Drain Current①	42	1	
P <sub>D</sub> @T <sub>A</sub> = 25°C	Maximum Power Dissipation®	2.4	W	
P <sub>D</sub> @T <sub>A</sub> = 70°C	Maximum Power Dissipation③	1.7	W	
	Linear Derating Factor	16	mW/°C	
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy®	140	mJ	
I <sub>AR</sub>	Avalanche Current①	5.1	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy	See Fig. 14, 15, 16	mJ	
T <sub>J</sub> , T <sub>STG</sub>	Junction and Storage Temperature Range	-55 to + 175	°C	

## **Thermal Resistance**

	Parameter	Max.	Units
$R_{\theta JA}$	Maximum Junction-to-Ambient 3	62.5	°C/W



## Electrical Characteristics @ $T_J = 25^{\circ}C$ (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	55			٧	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.052		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		0.043	0.050		V <sub>GS</sub> = 10V, I <sub>D</sub> = 5.1A ②
T DS(on)	Static Brain to Source Off Hesistance		0.056	0.065	Ω	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 4.42A ②
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0			٧	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
9fs	Forward Transconductance	10.4			S	V <sub>DS</sub> = 10V, I <sub>D</sub> = 5.2A
1	Drain-to-Source Leakage Current			2.0		V <sub>DS</sub> = 44V, V <sub>GS</sub> = 0V
I <sub>DSS</sub>	Diali-10-30dice Leakage Current			25	μA	V <sub>DS</sub> = 44V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 150°C
lass	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	I IIA	$V_{GS} = -20V$
Qg	Total Gate Charge		29	44		I <sub>D</sub> = 5.2A
Q <sub>gs</sub>	Gate-to-Source Charge		2.9	4.4	nC	$V_{DS} = 44V$
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge		7.3	11		$V_{GS} = 10V$
t <sub>d(on)</sub>	Turn-On Delay Time		9.2			V <sub>DD</sub> = 28V
t <sub>r</sub>	Rise Time		7.7		ne l	$I_{D} = 1.0A$
t <sub>d(off)</sub>	Turn-Off Delay Time $$ 31 $$ ns $R_G = 6.0\Omega$		$R_G = 6.0\Omega$			
t <sub>f</sub>	Fall Time		12.5			V <sub>GS</sub> = 10V ②
C <sub>iss</sub>	Input Capacitance		780			V <sub>GS</sub> = 0V
Coss	Output Capacitance		190		pF	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		66			f = 1.0MHz

## **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			2.4	_	MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			42	- A	integral reverse p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage			1.2	V	$T_J = 25^{\circ}C$ , $I_S = 2.6A$ , $V_{GS} = 0V$ ②
t <sub>rr</sub>	Reverse Recovery Time		51	77	ns	$T_J = 25^{\circ}C, I_F = 2.6A$
Q <sub>rr</sub>	Reverse Recovery Charge		76	114	nC	di/dt = 100A/µs ②

### Notes:

① Repetitive rating; pulse width limited by max. junction temperature.

② Pulse width  $\leq$  300 $\mu$ s; duty cycle  $\leq$  2%.

③ Surface mounted on FR-4 board, t ≤ 10sec.



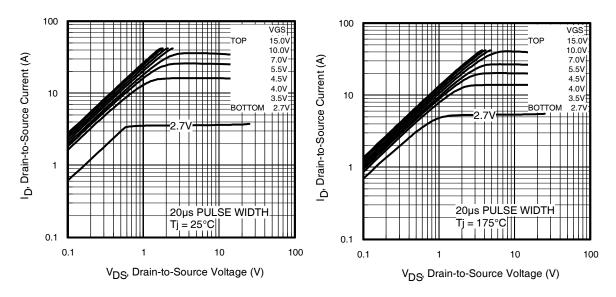


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

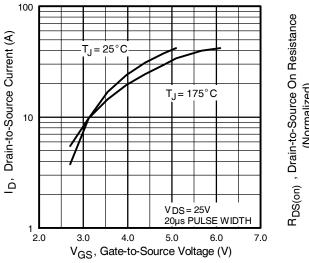
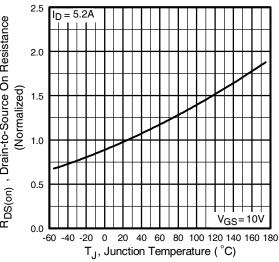
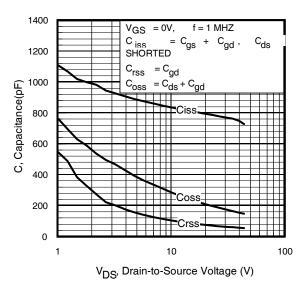


Fig 3. Typical Transfer Characteristics

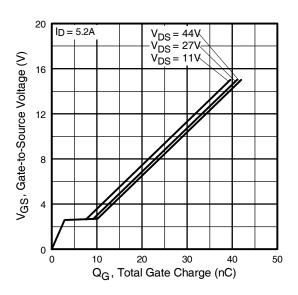


**Fig 4.** Normalized On-Resistance Vs. Temperature

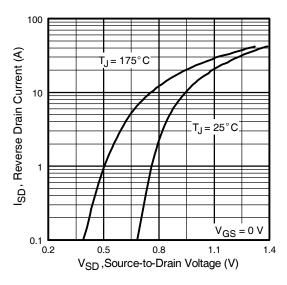




**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

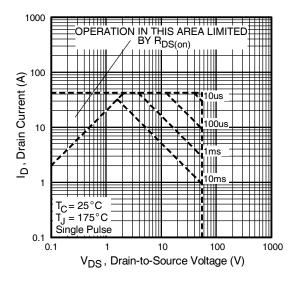
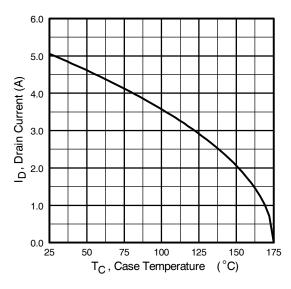


Fig 8. Maximum Safe Operating Area





**Fig 9.** Maximum Drain Current Vs. Case Temperature

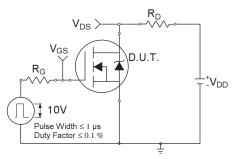


Fig 10a. Switching Time Test Circuit

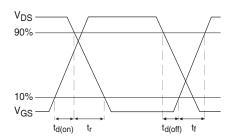


Fig 10b. Switching Time Waveforms

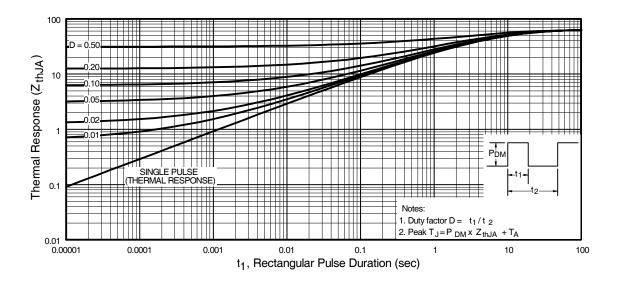
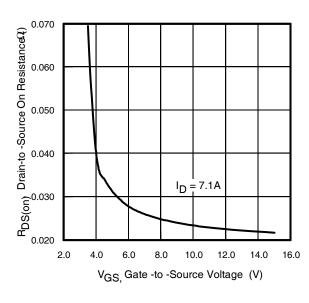
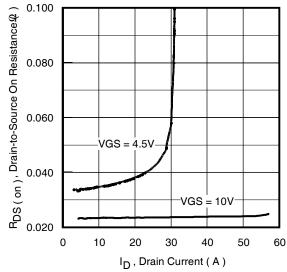


Fig 10. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient







**Fig 11.** Typical On-Resistance Vs. Gate Voltage

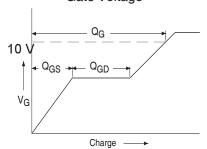


Fig 13a. Basic Gate Charge Waveform

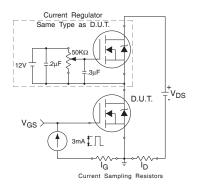
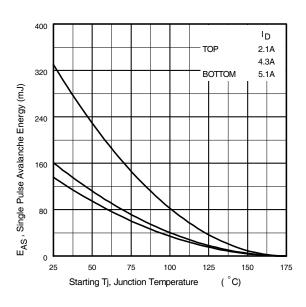


Fig 13b. Gate Charge Test Circuit

**Fig 12.** Typical On-Resistance Vs. Drain Current



**Fig 14.** Maximum Avalanche Energy Vs. Drain Current



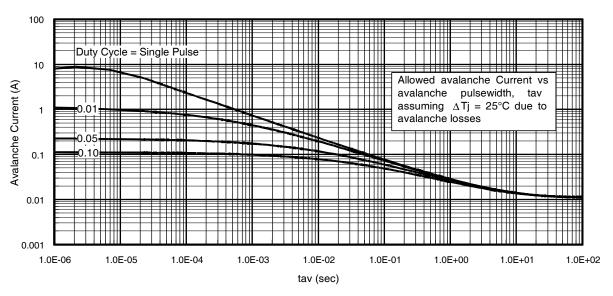
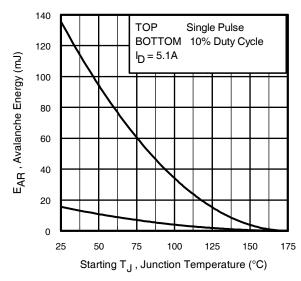


Fig 15. Typical Avalanche Current Vs. Pulsewidth



**Fig 16.** Maximum Avalanche Energy Vs. Temperature

# Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

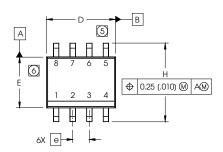
- 1. Avalanche failures assumption:
  - Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long  $asT_{jmax}$  is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 15, 16).
  - $t_{av}$  = Average time in avalanche.
  - $D = Duty cycle in avalanche = t_{av} \cdot f$
  - $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D \; (ave)} = 1/2 \; (\; 1.3 \cdot \text{BV} \cdot \text{I}_{av}) &= \triangle \text{T} / \, \text{Z}_{thJC} \\ \text{I}_{av} = 2\triangle \text{T} / \; [1.3 \cdot \text{BV} \cdot \text{Z}_{th}] \\ \text{E}_{AS \; (AR)} = P_{D \; (ave)} \cdot t_{av} \end{split}$$



## SO-8 Package Outline(Mosfet & Fetky)

Dimensions are shown in milimeters (inches)



	D	.013	.020	0.33	0.51	
	C	.0075	.0098	0.19	0.25	
	D	.189	.1968	4.80	5.00	
	Е	.1497	.1574	3.80	4.00	
	е	.050 B	ASIC	1.27 B	ASIC	
	еl	.025 B	ASIC	0.635 E	BASIC	
	Н	.2284	.2440	5.80	6.20	
	K	.0099	.0196	0.25	0.50	
	L	.016	.050	0.40	1.27	
	У	0°	8°	0°	8°	
— K x 45°						

INCHES

MIN MAX

.0688 1.35

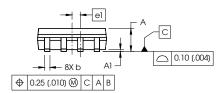
A1 .0040 .0098 0.10 0.25

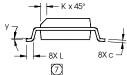
.0532

MILLIMETERS

MIN MAX

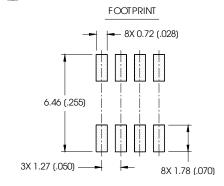
1.75



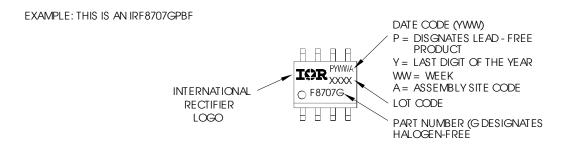


#### NOTES:

- 1. DIMENSIONING & TOLERANGING PER ASME Y14.5M-1994.
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
- (5) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 (.006).
- (6) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.010).
- 7 DISTRICT OF LEAD FOR SOLDERING TO



## SO-8 Part Marking Information

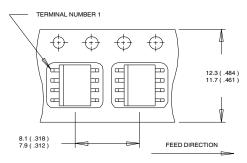


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



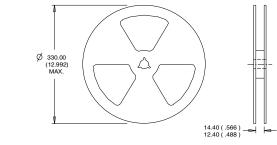
## **SO-8 Tape and Reel**

Dimensions are shown in millimeters (inches)



#### NOTES:

- CONTROLLING DIMENSION: MILLIMETER.
  ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
  OUTLINE CONFORMS TO EIA-481 & EIA-541.



- NOTES:
  1. CONTROLLING DIMENSION: MILLIMETER.
  2. OUTLINE CONFORMS TO EIA-481 & EIA-541

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

#### Qualification information<sup>†</sup>

Qualification level	Industrial (per JEDEC JES D47F <sup>††</sup> guidelines)			
Moisture Sensitivity Level	SO-8	MSL1 (per JEDEC J-STD-020D <sup>††</sup> )		
RoHS compliant	Yes			

- † Qualification standards can be found at International Rectifier's web site: http://www.irf.com/product-info/reliability
- †† Applicable version of JEDEC standard at the time of product release



IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA To contact International Rectifier, please visit http://www.irf.com/whoto-call/

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